

<b>Notice of References Cited</b>	Application/Control No. 10/575,338		Applicant(s)/Patent Under Reexamination MAKII ET AL.	
	Examiner ANCA EOFF		Art Unit 1795	Page 1 of 1

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*	B	US-2005/0147914	07-2005	Hatanaka et al.	430/270.1
*	C	US-5,648,194	07-1997	Pai et al.	430/165
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	N	WO 03/087941	10-2003		Hatanaka, T. et al.	
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#### NON-PATENT DOCUMENTS

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